

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Serial No.:	10/091,985	Confirmation No.:	6343
Applicant(s):	SUZUKI, et al.	Group Art Unit:	2877
		Examiner:	Lee, Hwa S.
Filed:	March 6, 2002		
		Customer No.:	27123

For: INTERFEROMETER AND INTERFERENCE MEASUREMENT METHOD

**REQUEST FOR SUPPLEMENTAL CERTIFICATE OF CORRECTION OF PATENT**

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Respectfully submitted,  
MORGAN & FINNEGAN, L.L.P.

Dated: June 20, 2007



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**UNITED STATES PATENT AND TRADEMARK OFFICE**  
**SUPPLEMENTAL CERTIFICATE OF CORRECTION**

PATENT NUMBER : 7,106,455 B2  
DATED : September 12, 2006  
INVENTOR(S) : Akiyoshi SUZUKI, Yoshiyuki SEKINE

It is certified that an error appears or errors appear in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

In the Title

INTERFEROMETER AND INTERFERENCE MEASUREMENT METHOD

Replace "INTERFERENCE" with – INTERFERENCE --

ADDRESS ASSOCIATED WITH CUSTOMER NUMBER:  
27123

PATENT NO. 7,106,455 B2

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This collection of information is required by 37 CFR 1.322, 1.323, and 1.324. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 1.0 hour to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Attention Certificate of Corrections Branch, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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(12) **United States Patent**  
**Suzuki et al.**(10) **Patent No.:** **US 7,106,455 B2**  
(45) **Date of Patent:** **Sep. 12, 2006**(54) **INTERFEROMETER AND INTERFERENCE MEASUREMENT METHOD**(75) **Inventors:** Akiyoshi Suzuki, Tokyo (JP);  
Yoshiyuki Sekine, Tochigi (JP)(73) **Assignee:** Canon Kabushiki Kaisha, Tokyo (JP)(\*) **Notice:** Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 187 days.

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(21) **Appl. No.:** 10/091,985(22) **Filed:** Mar. 6, 2002(65) **Prior Publication Data**

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(30) **Foreign Application Priority Data**Mar. 6, 2001 (JP) ..... 2001-062065  
Apr. 9, 2001 (JP) ..... 2001-109998(51) **Int. Cl.**  
**G01B 9/02** (2006.01)(52) **U.S. CL.** ..... 356/512; 356/513; 356/521;  
378/36(58) **Field of Classification Search** ..... 356/512,  
356/513, 521, 511; 378/36  
See application file for complete search history.(56) **References Cited****U.S. PATENT DOCUMENTS**

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**Primary Examiner**—Andrew H. Lee(74) **Attorney, Agent, or Firm**—Morgan & Finnegan, L.L.P.(57) **ABSTRACT**

There is provided an interferometer for measuring a surface shape of an optical element using interference, including a reference wave-front generating unit for generating a reference wave front for measuring the surface shape, which is provided in a target optical path, and includes an Alvarez lens.

**33 Claims, 10 Drawing Sheets**